

September 1998

Dual 2-to-4-Line Decoder/Demultiplexer

Features

- Buffered Inputs
- Typical Propagation Delay
 - 5.4ns at $V_{CC} = 5V$, $T_A = 25^{\circ}C$, $C_L = 50pF$
- Exceeds 2kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-Resistant CMOS Process and Circuit Design
- Speed of Bipolar FAST™/AS/S with Significantly Reduced Power Consumption
- Balanced Propagation Delays
- AC Types Feature 1.5V to 5.5V Operation and Balanced Noise Immunity at 30% of the Supply
- $\pm 24mA$ Output Drive Current
 - Fanout to 15 FAST™ ICs
 - Drives 50 Ω Transmission Lines

Description

The CD74AC139 and CD74ACT139 are dual 2-to-4-line decoders/demultiplexers that utilize the Harris Advanced CMOS Logic technology. These devices contain two independent binary to one-of-four decoders, each with a single active LOW enable input ($\overline{1E}$ or $\overline{2E}$). Data on the select inputs (1A0 and 1A1 or 2A0 and 2A1) cause one of the four normally HIGH outputs to go LOW.

If the enable input is HIGH, all four outputs remain HIGH. For demultiplexer operation, the enable input is the data input. The enable input also functions as a chip select when these devices are cascaded.

Ordering Information

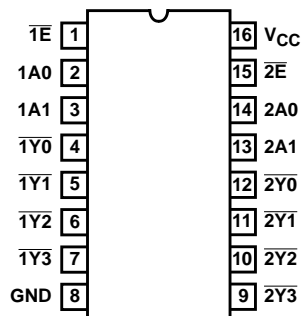
PART NUMBER	TEMP. RANGE ($^{\circ}C$)	PACKAGE	PKG. NO.
CD74AC139E	0 to 70 $^{\circ}C$, -40 to 85, -55 to 125	16 Ld PDIP	E16.3
CD74ACT139E	0 to 70 $^{\circ}C$, -40 to 85, -55 to 125	16 Ld PDIP	E16.3
CD74AC139M96	0 to 70 $^{\circ}C$, -40 to 85, -55 to 125	16 Ld SOIC	M16.15
CD74ACT139M	0 to 70 $^{\circ}C$, -40 to 85, -55 to 125	16 Ld SOIC	M16.15

NOTES:

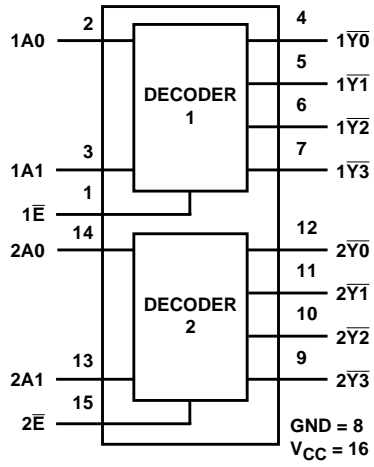
1. When ordering, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.
2. Wafer and die for this part number is available which meets all electrical specifications. Please contact your local sales office or Harris customer service for ordering information.

Pinout

CD74AC139, CD74ACT139
(PDIP, SOIC)
TOP VIEW



Functional Diagram



TRUTH TABLE

INPUTS			OUTPUTS			
ENABLE	SELECT		$\overline{Y3}$	$\overline{Y2}$	$\overline{Y1}$	$\overline{Y0}$
\overline{E}	A1	A0				
L	L	L	H	H	H	L
L	L	H	H	H	L	H
L	H	L	H	L	H	H
L	H	H	L	H	H	H
H	X	X	H	H	H	H

X = Don't Care

CD74AC139, CD74ACT139

Absolute Maximum Ratings

DC Supply Voltage, V_{CC}	-0.5V to 6V
DC Input Diode Current, I_{IK}	
For $V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$	$\pm 20mA$
DC Output Diode Current, I_{OK}	
For $V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$	$\pm 50mA$
DC Output Source or Sink Current per Output Pin, I_O	
For $V_O > -0.5V$ or $V_O < V_{CC} + 0.5V$	$\pm 50mA$
DC V_{CC} or Ground Current, I_{CC} or I_{GND} (Note 3)	$\pm 100mA$

Thermal Information

Thermal Resistance (Typical, Note 5)	θ_{JA} (°C/W)
PDIP Package	90
SOIC Package	160
Maximum Junction Temperature (Plastic Package)	150°C
Maximum Storage Temperature Range	-65°C to 150°C
Maximum Lead Temperature (Soldering 10s)	300°C

Operating Conditions

Temperature Range, T_A	-55°C to 125°C
Supply Voltage Range, V_{CC} (Note 4)	
AC Types	1.5V to 5.5V
ACT Types	4.5V to 5.5V
DC Input or Output Voltage, V_I , V_O	0V to V_{CC}
Input Rise and Fall Slew Rate, dt/dv	
AC Types, 1.5V to 3V	50ns (Max)
AC Types, 3.6V to 5.5V	20ns (Max)
ACT Types, 4.5V to 5.5V	10ns (Max)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTES:

3. For up to 4 outputs per device, add $\pm 25mA$ for each additional output.
4. Unless otherwise specified, all voltages are referenced to ground.
5. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

DC Electrical Specifications

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS	
		V_I (V)	I_O (mA)		MIN	MAX	MIN	MAX	MIN	MAX		
AC TYPES												
High Level Input Voltage	V_{IH}	-	-	1.5	1.2	-	1.2	-	1.2	-	V	
				3	2.1	-	2.1	-	2.1	-	V	
				5.5	3.85	-	3.85	-	3.85	-	V	
Low Level Input Voltage	V_{IL}	-	-	1.5	-	0.3	-	0.3	-	0.3	V	
				3	-	0.9	-	0.9	-	0.9	V	
				5.5	-	1.65	-	1.65	-	1.65	V	
High Level Output Voltage	V_{OH}	V_{IH} or V_{IL}	-0.05	-0.05	1.5	1.4	-	1.4	-	1.4	-	V
			-0.05	-0.05	3	2.9	-	2.9	-	2.9	-	V
			-0.05	-0.05	4.5	4.4	-	4.4	-	4.4	-	V
			-4	-4	3	2.58	-	2.48	-	2.4	-	V
			-24	-24	4.5	3.94	-	3.8	-	3.7	-	V
			-75 (Note 6, 7)	-75 (Note 6, 7)	5.5	-	-	3.85	-	-	-	V
-50 (Note 6, 7)	-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	V			

CD74AC139, CD74ACT139

DC Electrical Specifications (Continued)

PARAMETER	SYMBOL	TEST CONDITIONS		V _{CC} (V)	25°C		-40°C TO 85°C		-55°C TO 125°C		UNITS	
		V _I (V)	I _O (mA)		MIN	MAX	MIN	MAX	MIN	MAX		
Low Level Output Voltage	V _{OL}	V _{IH} or V _{IL}	0.05	1.5	-	0.1	-	0.1	-	0.1	V	
			0.05	3	-	0.1	-	0.1	-	0.1	V	
			0.05	4.5	-	0.1	-	0.1	-	0.1	V	
			12	3	-	0.36	-	0.44	-	0.5	V	
			24	4.5	-	0.36	-	0.44	-	0.5	V	
			75 (Note 6, 7)	5.5	-	-	-	1.65	-	-	V	
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	V	
Input Leakage Current	I _I	V _{CC} or GND	-	5.5	-	±0.1	-	±1	-	±1	μA	
Quiescent Supply Current MSI	I _{CC}	V _{CC} or GND	0	5.5	-	8	-	80	-	160	μA	
ACT TYPES												
High Level Input Voltage	V _{IH}	-	-	4.5 to 5.5	2	-	2	-	2	-	V	
Low Level Input Voltage	V _{IL}	-	-	4.5 to 5.5	-	0.8	-	0.8	-	0.8	V	
High Level Output Voltage	V _{OH}	V _{IH} or V _{IL}	-0.05	4.5	4.4	-	4.4	-	4.4	-	4.4	V
			-24	4.5	3.94	-	3.8	-	3.7	-	3.7	V
			-75 (Note 6, 7)	5.5	-	-	3.85	-	-	-	-	V
			-50 (Note 6, 7)	5.5	-	-	-	-	3.85	-	-	V
Low Level Output Voltage	V _{OL}	V _{IH} or V _{IL}	0.05	4.5	-	0.1	-	0.1	-	0.1	V	
			24	4.5	-	0.36	-	0.44	-	0.5	V	
			75 (Note 6, 7)	5.5	-	-	-	1.65	-	-	V	
			50 (Note 6, 7)	5.5	-	-	-	-	-	1.65	V	
Input Leakage Current	I _I	V _{CC} or GND	-	5.5	-	±0.1	-	±1	-	±1	μA	
Quiescent Supply Current MSI	I _{CC}	V _{CC} or GND	0	5.5	-	8	-	80	-	160	μA	
Additional Supply Current per Input Pin TTL Inputs High 1 Unit Load	ΔI _{CC}	V _{CC} -2.1	-	4.5 to 5.5	-	2.4	-	2.8	-	3	mA	

NOTES:

6. Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.
7. Test verifies a minimum 50Ω transmission-line-drive capability at 85°C, 75Ω at 125°C.

ACT Input Load Table

INPUT	UNIT LOAD
A0, A1	1
\bar{E}	0.67

NOTE: Unit load is ΔI_{CC} limit specified in DC Electrical Specifications Table, e.g., 2.4mA max at 25°C.

CD74AC139, CD74ACT139

Switching Specifications Input t_r , $t_f = 3\text{ns}$, $C_L = 50\text{pF}$ (Worst Case)

PARAMETER	SYMBOL	V_{CC} (V)	-40°C TO 85°C			-55°C TO 125°C			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	
AC TYPES									
Propagation Delay, A0, A1 to Outputs	t_{PLH} , t_{PHL}	1.5	-	-	119	-	-	131	ns
		3.3 (Note 9)	3.9	-	13.4	3.7	-	14.7	ns
		5 (Note 10)	2.8	-	9.5	2.6	-	10.5	ns
Propagation Delay, \bar{E} to Outputs	t_{PLH} , t_{PHL}	1.5	-	-	119	-	-	131	ns
		3.1	3.9	-	13.4	3.7	-	14.7	ns
		5	2.8	-	9.5	2.6	-	10.5	ns
Input Capacitance	C_I	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C_{PD} (Note 11)	-	-	83	-	-	83	-	pF
ACT TYPES									
Propagation Delay, A0, A1 to Outputs	t_{PLH} , t_{PHL}	5 (Note 10)	3.1	-	10.5	2.9	-	11.5	ns
Propagation Delay, \bar{E} to Outputs	t_{PLH} , t_{PHL}	5	3.2	-	10.9	3	-	12	ns
Input Capacitance	C_I	-	-	-	10	-	-	10	pF
Power Dissipation Capacitance	C_{PD} (Note 11)	-	-	83	-	-	83	-	pF

NOTES:

8. Limits tested at 100%.
9. 3.3V Min at 3.6V, Max at 3V.
10. 5V Min at 5.5V, Max at 4.5V.
11. C_{PD} is used to determine the dynamic power consumption per decoder/demultiplexer.
 AC: $P_D = V_{CC}^2 f_i (C_{PD} + C_L)$
 ACT: $P_D = V_{CC}^2 f_i (C_{PD} + C_L) + V_{CC} \Delta I_{CC}$ where f_i = input frequency, C_L = output load capacitance, V_{CC} = supply voltage.

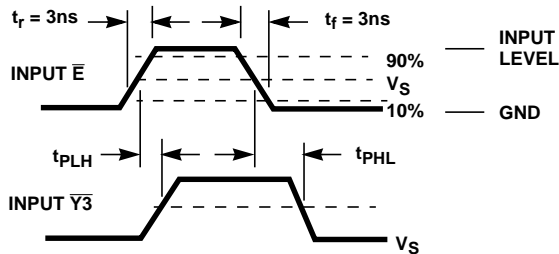


FIGURE 1.

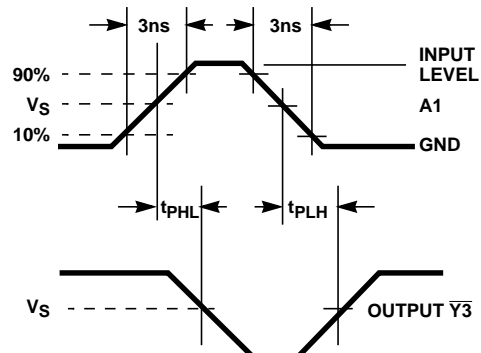
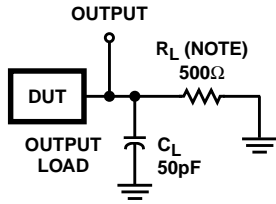


FIGURE 2.

CD74AC139, CD74ACT139



NOTE: For AC Series Only: When $V_{CC} = 1.5V$, $R_L = 1k\Omega$.

	CD74AC	CD74ACT
Input Level	V_{CC}	3V
Input Switching Voltage, V_S	$0.5 V_{CC}$	1.5V
Output Switching Voltage, V_S	$0.5 V_{CC}$	$0.5 V_{CC}$

FIGURE 3. PROPAGATION DELAY TIMES

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